

Notice of References Cited	Application/Control No. 10/567,883		Applicant(s)/Patent Under Reexamination STEIN ET AL.	
	Examiner Feifei Yeung-Lopez		Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,977,565	11-1999	Ishikawa et al.	257/81
*	B	US-6,072,148	06-2000	Azdasht, Ghassem	219/121.63
*	C	US-6,515,308	02-2003	Kneissl et al.	257/86
*	D	US-6,573,537	06-2003	Steigerwald et al.	257/103
*	E	US-6,614,056	09-2003	Tarsa et al.	257/91
*	F	US-6,657,236	12-2003	Thibeault et al.	257/98
*	G	US-2002/0131462	09-2002	Lin et al.	372/43
*	H	US-2003/0136442	07-2003	Takamoto, Tatsuya	136/262
*	I	US-2004/0120375	06-2004	Kwon, Hoki	372/045
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.